## Application/Control No. Applicant(s)/Patent Under Reexamination LAMACCHIA ET AL. Examiner Jung W Kim U.S. PATENT DOCUMENTS Applicant(s)/Patent Under Reexamination LAMACCHIA ET AL. Page 1 of 1

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,052,678	04-2000	Itoh et al.	706/13
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